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Kind regards,

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N-channel 25 V 2.8 m Ω logic level MOSFET in LFPAK Rev. 3 — 21 December 2011 Product

Product data sheet

Product profile 1.

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOSTM technology

1.2 Features and benefits

- Low thermal resistance
- Low threshold voltage

- Optimized for use in DC-to-DC converters
- Very low switching and conduction losses

1.3 Applications

- DC-to-DC convertors
- Notebook computers

- Switched-mode power supplies
- Voltage regulators

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	-	25	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	100	Α
Static characte	eristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	2	2.8	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	3	4.1	mΩ
Dynamic char	acteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; V_{DS} = 12 \text{ V};$	-	7.3	-	nC
$Q_{G(tot)}$	total gate charge	see Figure 11; see Figure 12	-	32	-	nC



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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	D
3	S	source		
4	G	gate	9	
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK; Power-SO8)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH2625L	LFPAK; Power-SO8	plastic single-ended surface-mounted package; 4 leads	SOT669

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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	25	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	25	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{M}}$	-	63	Α
		$V_{GS} = 10 \text{ V}$; $T_{mb} = 25 \text{ °C}$; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	100	Α
I _{DM}	peak drain current	pulsed; $t_p \le 10 \mu s$; $T_{mb} = 25 °C$; see Figure 3	-	300	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	62.5	W
T _{stg}	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-drai	n diode				
Is	source current	T _{mb} = 25 °C	-	52	Α
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$	-	156	Α
Avalanche r	uggedness				
E _{DS(AL)R}	repetitive drain-source avalanche energy	unclamped; t_p = 0.01 ms; R_{GS} = 50 Ω ; V_{GS} = 10 V; I_D = 7.1 A; V_{sup} ≤ 25 V	[1][2] -	2.5	mJ
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 71 A; $V_{sup} \le$ 25 V; unclamped; t_p = 0.1 ms; R_{GS} = 50 Ω	-	250	mJ

^[1] Duty cycle is limited by the maximum junction temperature.

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^[2] Repetitive avalanche failure is not determined simply by thermal effects. Repetitive avalanche transients should only be applied for short bursts, not every switching cycle.

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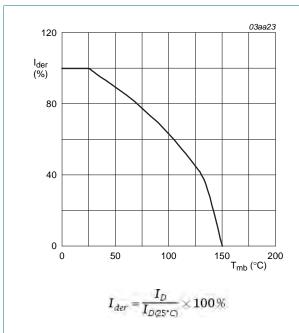


Fig 1. Normalized continuous drain current as a function of mounting base temperature

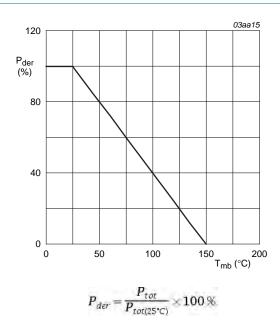
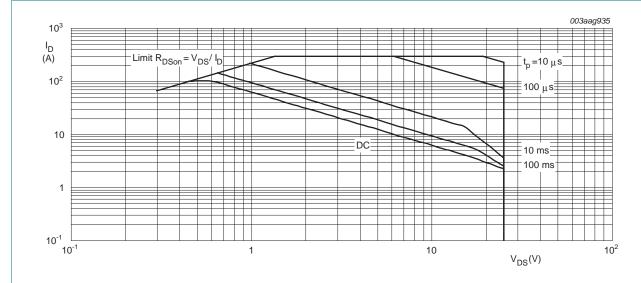


Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25^{\circ}C$: I_{DM} is a single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

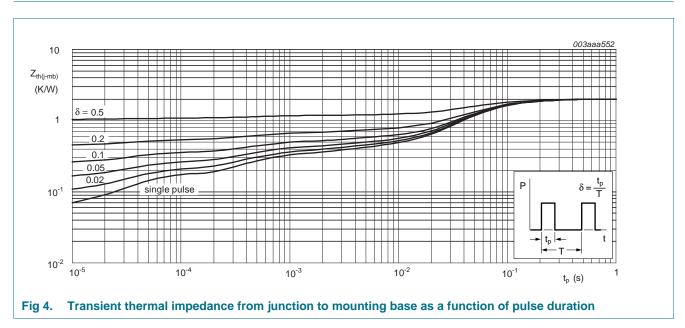
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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W



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6. Characteristics

Table 6. Characteristics

Table 0.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	25	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	-	-	2.2	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	1	1.5	2	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 150 \text{ °C}$; see <u>Figure 8</u>	0.5	-	-	V
I_{DSS}	drain leakage current	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.06	1	μΑ
		$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	500	μΑ
I_{GSS}	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nΑ
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nΑ
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 150 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	3.2	4.3	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 150 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	4.8	6.6	mΩ
	V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	2	2.8	mΩ	
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	3	4.1	mΩ
R_G	gate resistance	f = 1 MHz	-	1.5	-	Ω
Dynamic	characteristics					
$Q_{G(tot)}$	total gate charge	$I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	32	-	nC
		$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$	-	26	-	nC
Q_{GS}	gate-source charge	$I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$;	-	9.6	-	nC
Q _{GS1}	pre-threshold gate-source charge	see <u>Figure 11</u> ; see <u>Figure 12</u>	-	6	-	nC
Q _{GS2}	post-threshold gate-source charge		-	3.6	-	nC
Q_{GD}	gate-drain charge		-	7.3	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	2.2	-	V
C _{iss}	input capacitance	$V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 13}{\text{Figure } 14}$	-	4308	-	pF
		$V_{DS} = 0 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 ^{\circ}\text{C}$	-	4830	-	pF
C _{oss}	output capacitance	V _{DS} = 12 V; V _{GS} = 0 V; f = 1 MHz;	-	1137	-	pF
C _{rss}	reverse transfer capacitance	T _j = 25 °C; see <u>Figure 13</u> ; see <u>Figure 14</u>	-	439	-	pF

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Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$t_{d(on)}$	turn-on delay time	V_{DS} = 12 V; R_L = 0.48 Ω ; V_{GS} = 4.5 V;	-	41	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	52	-	ns
$t_{d(off)}$	turn-off delay time		-	67	-	ns
t _f	fall time		-	30	-	ns
Source-dra	in diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 15</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	47	-	ns
Q _r	recovered charge	$V_{DS} = 25 \text{ V}$	-	22	-	nC

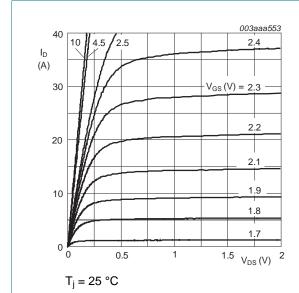
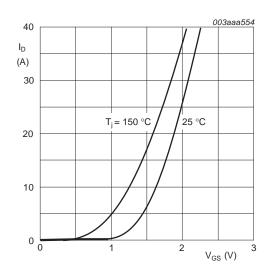


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical valuesT



 T_j = 25 °C and 150 °C; $V_{DS} > I_D X R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

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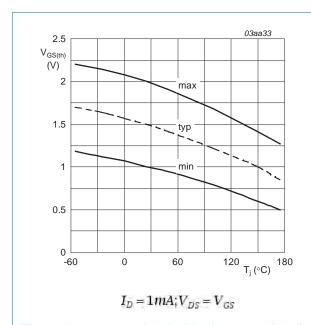


Fig 7. Gate-source threshold voltage as a function of junction temperature

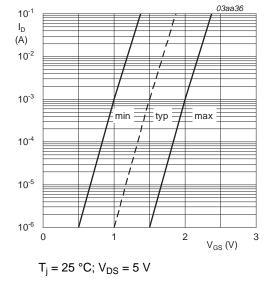


Fig 8. Sub-threshold drain current as a function of gate-source voltage

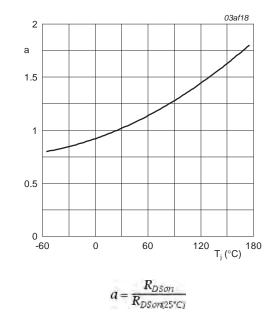


Fig 9. Normalized drain-source on-state resistance factor as a function of junction temperature

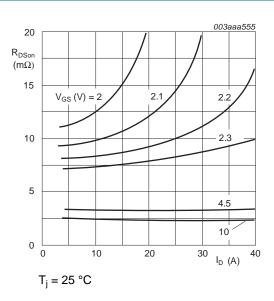


Fig 10. Drain-source on-state resistance as a function of drain current; typical values

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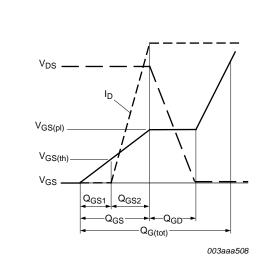


Fig 11. Gate charge waveform definitions

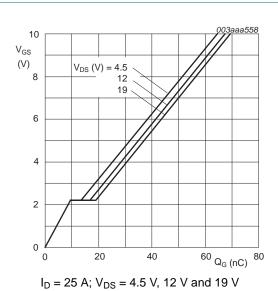
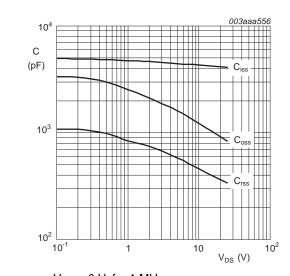


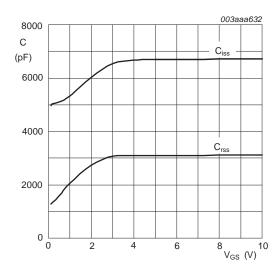
Fig 12. Gate-source voltage as a function of gate

charge; typical values



 $V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$

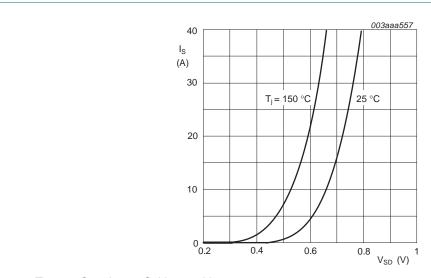
Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $V_{DS} = 0 V$; f = 1 MHz

Fig 14. Input and reverse transfer capacitances as a function of gate-source voltage; typical values

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 $T_j = 25$ °C and 150 °C; $V_{GS} = 0$ V

Fig 15. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

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PH2625L **NXP Semiconductors**

N-channel 25 V 2.8 mΩ logic level MOSFET in LFPAK

Package outline

Plastic single-ended surface-mounted package (LFPAK; Power-SO8); 4 leads

SOT669

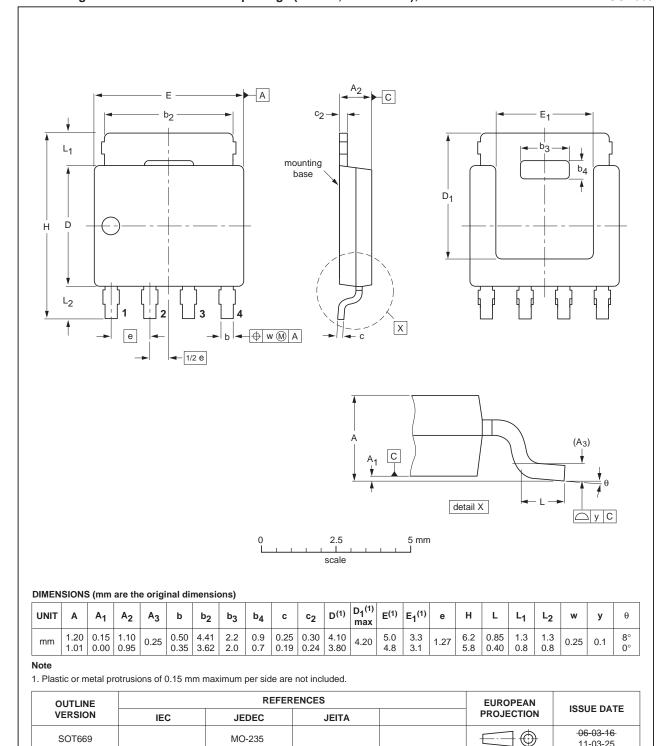


Fig 16. Package outline SOT669 (LFPAK; Power-SO8)

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N-channel 25 V 2.8 m Ω logic level MOSFET in LFPAK

8. Revision history

Table 7. Revision history

Danis and ID	Dalassa data	Data about status	01	0
Document ID	Release date	Data sheet status	Change notice	Supersedes
PH2625L v.3	20111221	Product data sheet	-	PH2625L_2
Modifications:	 Status change 	ed from preliminary to produc	t.	
	 The format of the NXP Semicon 		esigned to comply with	the new identity guidelines of
	 Legal texts ha 	ve been adapted to the new	company name where	appropriate.
PH2625L_2 (9397 750 12306)	20050224	Preliminary data shee	t -	PH2625L-01

N-channel 25 V 2.8 mΩ logic level MOSFET in LFPAK

9. Legal information

9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design
- [2] The term 'short data sheet' is explained in section "Definitions".
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